Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10579504	KIM ET AL.
Examiner	Art Unit
Skowronek, Karlheinz R	1631

SEARCHED					
Class	Subclass	Date	Examine		

SEARCH NOTES				
Search Notes	Date	Examiner		
Search Terms: GENE ONTOLOGY, DATABASE, CLUSTER ANALYSIS, MICROARRAY, BIOCHIP ARRAY, NUMERICAL VALUE, DATA MINING, GRAPH THEORY, DIRECTED ACYCLIC GRAPH; Inventor search	4/10/2007	KRS		
EAST: Search Terms	4/10/2007	KRS		
Google: Search Terms	4/10/2007	KRS		

INTERFERENCE SEARCH					
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